To compare solid and faulty cards, contact probe and card chassis. Compare by touching the same points of both cards.

Ch.1 and Ch2 are harmonious graphs

ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.
Comparison of two cards

Ch.1 and Ch.2 are not harmonious

ATTENTION: Probe must be at 1x position. High-voltage capacitors must be emptied by using a resistor.
Comparison of two cards

Graph 3 is not 100% harmonious!

ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

Reference: Ch1
D1: 0.9 V
D2: 0.25 V

Test: Ch2
D1: 0.95 V
D2: 0.35 V

Tolerance (%): 3
ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

Reference: Ch1
C : 4.4 μF

Test: Ch2

Open Circuit
Ch.1 (Red) is low quality and Ch.2 (Blue) is bad capacitor.

Click for capacitor test

Capacitor generates parallel resistor. This capacitor generates heath at high frequency

Reference: Ch1
C : 47 μF

Test:
R : 535 Ohm
C : 48 μF
Both of two probes are used to test 3-Pin active components. Probe chassis is connected to transistor emitter. Probes' pins are connected to base and collector.

Triac, Tristor, Transistor, FET and IGBT Test

ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.
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Reference:

Tristor

Test:

Ch1

Ch2

Tristor (G)

Tristor (A)
ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

Refernce: NPN Transistor

Test: Ch1

Ch2

Tolerance (%) 3
ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

Reference:

N FET

Test:

Ch1

Ch2

FET N (G)

FET N (D)
ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

If low current is selected, capacity of gate becomes more clear at graph (Ch.1).
ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

Reference:
NPN Transistor

Test:
Ch1
Ch2

Tolerance (%): 3
IGBT working but, current leakage at negative voltage!

ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.
1- Click to 'Record' button.
2- Write card code as the new folder name.
3- Click to 'New Folder' button.
4- Touch the point to be saved with Ch.1
5- Write a name that will remind you this point at 'New Point'
6- Click to 'Save' button.
Test with memorized data

1- Click to 'Record' button.
2- Select first data displayed on the screen
3- Click to 'Open' button.
Ch. 1 is memorized data. Touch the test point with probe of Ch. 2.

ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

Reference:
R: 458 Ohm
C: 441 µF

Test Point: 1
Auto. Test
Tolerance (%): 3

Open Circuit
Test with memorized data

Ch. 1 is memorized data. Touch the test point with probe of Ch. 2.

If auto test is active and test point is within the tolerance values, then next point is displayed.